Welcome to Galaxy Examinator reports

Date: Wed Sep 4 16:13:24 2024
Product :
LotID :

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Tests Statistics

Test	Name	Type	Low L.	High L.	Source	Execs	Fails	Mean	Sigma	Cp	Cpk	Yield
0	func_T1	F	n/a .	n/a .	Samples	50	0	n/a .	n/a .	n/a .	n/a .	100.00 %
1	func_T2	F	n/a .	n/a .	Samples	50	0	n/a .	n/a .	n/a .	n/a .	100.00 %
2	func_T3	F	n/a .	n/a .	Samples	50	0	n/a .	n/a .	n/a .	n/a .	100.00 %
3	Continuity_PPMU1 cs 19.g106	P	−1200 mV	−100 mV	Samples	50	0	−638.829 mV	0.739011 mV	248.1	243.0	100.00 %
4	Continuity_PPMU1 p20 19.g128	P	−1200 mV	−100 mV	Samples	50	0	−639.957 mV	1.16144 mV	157.9	155.0	100.00 %
5	Continuity_PPMU1 p21 19.g126	P	−1200 mV	−100 mV	Samples	50	0	−639.934 mV	1.19625 mV	153.3	150.5	100.00 %
6	Continuity_PPMU1 p22 19.e126	P	−1200 mV	−100 mV	Samples	50	0	−639.959 mV	1.1051 mV	165.9	162.9	100.00 %
7	Continuity_PPMU1 p23 19.e124	P	−1200 mV	−100 mV	Samples	50	0	−639.919 mV	1.04921 mV	174.7	171.5	100.00 %
8	Continuity_PPMU1 p40 19.e130	P	−1200 mV	−100 mV	Samples	50	0	−640.506 mV	1.31771 mV	139.1	136.7	100.00 %
9	Continuity_PPMU1 p41 19.e139	P	−1200 mV	−100 mV	Samples	50	0	−640.653 mV	1.33769 mV	137.1	134.7	100.00 %
10	Continuity_PPMU1 p42 19.e147	P	−1200 mV	−100 mV	Samples	50	0	−640.843 mV	1.15966 mV	158.1	155.5	100.00 %
11	Continuity_PPMU1 p43 19.e151	P	−1200 mV	−100 mV	Samples	50	0	−640.422 mV	1.26161 mV	145.3	142.8	100.00 %
12	Continuity_PPMU1 p50 19.e128	P	−1200 mV	−100 mV	Samples	50	0	−639.927 mV	1.26847 mV	144.5	141.9	100.00 %
13	Continuity_PPMU1 p51 19.g149	P	−1200 mV	−100 mV	Samples	50	0	−636.727 mV	0.591955 mV	309.7	302.2	100.00 %
14	Continuity_PPMU1 p52 19.g137	P	−1200 mV	−100 mV	Samples	50	0	−638.425 mV	1.29891 mV	141.1	138.2	100.00 %
15	Continuity_PPMU1 p53 19.e135	P	−1200 mV	−100 mV	Samples	50	0	−638.366 mV	1.30317 mV	140.7	137.7	100.00 %
16	Continuity_PPMU1 p60 19.g130	P	−1200 mV	−100 mV	Samples	50	0	−638.001 mV	1.37306 mV	133.5	130.6	100.00 %
17	Continuity_PPMU1 p61 19.g104	P	−1200 mV	−100 mV	Samples	50	0	−637.976 mV	1.15666 mV	158.5	155.0	100.00 %
18	Continuity_PPMU1 p62 19.g102	P	−1200 mV	−100 mV	Samples	50	0	−637.975 mV	1.14359 mV	160.3	156.8	100.00 %
19	Continuity_PPMU1 p63 19.e102	P	−1200 mV	−100 mV	Samples	50	0	−637.907 mV	1.04194 mV	176.0	172.1	100.00 %
20	Continuity_PPMU1 p70 19.g139	P	−1200 mV	−100 mV	Samples	50	0	−640.186 mV	1.3308 mV	137.8	135.3	100.00 %
21	Continuity_PPMU1 p71 19.e147	P	−1200 mV	−100 mV	Samples	50	0	−638.457 mV	1.2443 mV	147.3	144.2	100.00 %
22	Continuity_PPMU1 p72 19.e104	P	−1200 mV	−100 mV	Samples	50	0	−637.939 mV	0.945071 mV	194.0	189.7	100.00 %
23	Continuity_PPMU1 p73 19.e108	P	−1200 mV	−100 mV	Samples	50	0	−637.672 mV	1.03732 mV	176.7	172.8	100.00 %
24	Continuity_PPMU1 prog 19.g124	P	−1200 mV	−100 mV	Samples	50	0	−640.068 mV	0.916834 mV	200.0	196.4	100.00 %
25	SeqLeakage1 p20 19.g128	P	−30 uA	10 uA	Samples	50	0	−0.659074 uA	0.0257602 uA	258.8	137.9	100.00 %
26	SeqLeakage1 p21 19.g126	P	−30 uA	10 uA	Samples	50	0	−0.659128 uA	0.0273613 uA	243.7	129.9	100.00 %
27	SeqLeakage1 p22 19.e126	P	−30 uA	10 uA	Samples	50	0	−0.659499 uA	0.0238835 uA	279.1	148.8	100.00 %
28	SeqLeakage1 p23 19.e124	P	−30 uA	10 uA	Samples	50	0	−0.662982 uA	0.0224599 uA	296.8	158.3	100.00 %
29	SeqLeakage2 cs 19.g106	P	−30 uA	10 uA	Samples	50	0	0.00442263 uA	0.00836942 uA	796.6	398.1	100.00 %
30	SeqLeakage2 prog 19.g124	P	−30 uA	10 uA	Samples	50	0	0.0017725 uA	0.0110325 uA	604.3	302.1	100.00 %
31	VBT_outpleakage1 p40 19.e130	P	−10 uA	20 uA	Samples	50	0	−0.000566971 uA	0.0114804 uA	435.5	290.3	100.00 %
Test	Name	Type	Low L.	High L.	Source	Execs	Fails	Mean	Sigma	Cp	Cpk	Yield
32	VBT_outpleakage1 p41 19.e139	P	−10 uA	20 uA	Samples	50	0	0.000428692 uA	0.00803862 uA	622.0	414.7	100.00 %
33	VBT_outpleakage1 p42 19.e147	P	−10 uA	20 uA	Samples	50	0	0.0015068 uA	0.0102733 uA	486.7	324.5	100.00 %
34	VBT_outpleakage1 p43 19.e151	P	−10 uA	20 uA	Samples	50	0	−0.00103971 uA	0.00867403 uA	576.4	384.2	100.00 %
35	VBT_outpleakage1 p50 19.e128	P	−10 uA	20 uA	Samples	50	0	0.00120289 uA	0.010007 uA	499.6	333.1	100.00 %
36	VBT_outpleakage1 p51 19.g149	P	−10 uA	20 uA	Samples	50	0	0.00202032 uA	0.00936446 uA	533.9	356.0	100.00 %

Test	Name	Type	Low L.	High L.	Source	Execs	Fails	Mean	Sigma	Cp	Cpk	Yield
37	VBT_outpleakage1 p52 19.e137	P	−10 uA	20 uA	Samples	50	0	−0.00105678 uA	0.011461 uA	436.3	290.8	100.00 %
38	VBT_outpleakage1 p53 19.e135	P	−10 uA	20 uA	Samples	50	0	−0.00277265 uA	0.00892291 uA	560.4	373.5	100.00 %
39	VBT_outpleakage1 p60 19.g130	P	−10 uA	20 uA	Samples	50	0	0.000290797 uA	0.00921436 uA	542.6	361.8	100.00 %
40	VBT_outpleakage1 p61 19.g104	P	−10 uA	20 uA	Samples	50	0	0.00413707 uA	0.0114122 uA	438.1	292.2	100.00 %
41	VBT_outpleakage1 p62 19.g102	P	−10 uA	20 uA	Samples	50	0	0.00719384 uA	0.0160235 uA	312.0	208.2	100.00 %
42	VBT_outpleakage1 p63 19.e102	P	−10 uA	20 uA	Samples	50	0	0.00176909 uA	0.00954362 uA	523.9	349.3	100.00 %
43	VBT_outpleakage1 p70 19.g139	P	−10 uA	20 uA	Samples	50	0	−0.00163175 uA	0.00925232 uA	540.4	360.2	100.00 %
44	VBT_outpleakage1 p71 19.g147	P	−10 uA	20 uA	Samples	50	0	0.00596628 uA	0.00833879 uA	599.6	400.0	100.00 %
45	VBT_outpleakage1 p72 19.e104	P	−10 uA	20 uA	Samples	50	0	−0.00100623 uA	0.011639 uA	429.6	286.4	100.00 %
46	VBT_outpleakage1 p73 19.e108	P	−10 uA	20 uA	Samples	50	0	0.00117388 uA	0.0113674 uA	439.9	293.3	100.00 %
47	OutputZ_leak_vbt1 p40 19.e130	P	−10 uA	20 uA	Samples	50	0	−0.00107265 uA	0.0102458 uA	488.0	325.3	100.00 %
48	OutputZ_leak_vbt1 p41 19.e139	P	−10 uA	20 uA	Samples	50	0	0.00174539 uA	0.008824 uA	566.6	377.8	100.00 %
49	OutputZ_leak_vbt1 p42 19.e147	P	−10 uA	20 uA	Samples	50	0	0.000867551 uA	0.00898146 uA	556.7	371.2	100.00 %
50	OutputZ_leak_vbt1 p43 19.e151	P	−10 uA	20 uA	Samples	50	0	0.00211 uA	0.0095082 uA	525.9	350.6	100.00 %
51	OutputZ_leak_vbt1 p50 19.e128	P	−10 uA	20 uA	Samples	50	0	0.00216216 uA	0.00949243 uA	526.7	351.2	100.00 %
52	OutputZ_leak_vbt1 p51 19.g149	P	−10 uA	20 uA	Samples	50	0	0.00180604 uA	0.00824136 uA	606.7	404.5	100.00 %
53	OutputZ_leak_vbt1 p52 19.e137	P	−10 uA	20 uA	Samples	50	0	0.00125588 uA	0.00863721 uA	578.9	386.0	100.00 %
54	OutputZ_leak_vbt1 p53 19.e135	P	−10 uA	20 uA	Samples	50	0	−0.0024832 uA	0.00997394 uA	501.3	334.1	100.00 %
55	OutputZ_leak_vbt1 p60 19.g130	P	−10 uA	20 uA	Samples	50	0	−0.000566289 uA	0.00868435 uA	575.7	383.8	100.00 %
56	OutputZ_leak_vbt1 p61 19.g104	P	−10 uA	20 uA	Samples	50	0	0.00305319 uA	0.0096245 uA	519.5	346.4	100.00 %
57	OutputZ_leak_vbt1 p62 19.g102	P	−10 uA	20 uA	Samples	50	0	0.00472956 uA	0.00829177 uA	603.0	402.2	100.00 %
58	OutputZ_leak_vbt1 p63 19.e102	P	−10 uA	20 uA	Samples	50	0	−0.000228761 uA	0.0106321 uA	470.3	313.5	100.00 %
59	OutputZ_leak_vbt1 p70 19.g139	P	−10 uA	20 uA	Samples	50	0	−0.00215024 uA	0.00756443 uA	661.0	440.6	100.00 %
60	OutputZ_leak_vbt1 p71 19.g147	P	−10 uA	20 uA	Samples	50	0	0.00279142 uA	0.0116121 uA	430.6	287.1	100.00 %
61	OutputZ_leak_vbt1 p72 19.e104	P	−10 uA	20 uA	Samples	50	0	0.000213443 uA	0.010307 uA	485.1	323.4	100.00 %
62	OutputZ_leak_vbt1 p73 19.e108	P	−10 uA	20 uA	Samples	50	0	0.00324722 uA	0.00959745 uA	521.0	347.4	100.00 %
63	func_T4	F	n/a .	n/a .	Samples	50	0	n/a .	n/a .	n/a .	n/a .	100.00 %
Test	**Name**	**Type**	**Low L.**	**High L.**	**Source**	**Execs**	**Fails**	**Mean**	**Sigma**	**Cp**	**Cpk**	**Yield**
64	icc_static_vbt11 vcc 15.e201 <> Icc_static	P	10 uA	500 uA	Samples	50	0	21.2436 uA	0.217199 uA	376.0	17.26	100.00 %
65	Icc_dynamic vcc 15.e201 <> Icc_dynamic	P	10 uA	500 uA	Samples	50	0	20.7699 uA	0.419498 uA	194.7	8.56	100.00 %
67	func_T5 p50 19.e128	P	n/a .	n/a .	Samples	50	0	0.14524	0.00239523	n/a .	n/a .	100.00 %
68	func_T5 p50 19.e128	P	n/a .	n/a .	Samples	50	0	3.28306	0.00186714	n/a .	n/a .	100.00 %
71	func_T6 p50 19.e128	P	150 ns	350 ns	Samples	50	0	231.072 ns	0.883186 ns	37.74	30.60	100.00 %
72	func_T6 p50 19.e128	P	150 ns	350 ns	Samples	50	0	246.928 ns	0.813919 ns	40.95	39.70	100.00 %
73	func_T6 A8 0	P	1 ns	100 ns	Samples	50	0	15.856 ns	1.14503 ns	14.41	4.32	100.00 %
75	func_T7 p53 19.e135	P	n/a .	n/a .	Samples	50	0	3.28332 V	0.00218942 V	n/a .	n/a .	100.00 %
76	func_T7 p53 19.e135	P	n/a .	n/a .	Samples	50	0	0.13898	0.00240314	n/a .	n/a .	100.00 %
81	func_T8 A8 0	P	1 ns	20 ns	Samples	50	0	9.216 ns	1.58865 ns	1.99	1.72	100.00 %
786000	Soft_Bin parameter	–	n/a .	n/a .	Samples	50	0	1	0	n/a .	n/a .	100.00 %
786001	Hard_Bin parameter	–	n/a .	n/a .	Samples	50	0	1	0	n/a .	n/a .	100.00 %
786002	Die_X parameter	–	n/a .	n/a .	Samples	50	0	2.94	2.0445	n/a .	n/a .	100.00 %
786003	Die_Y parameter	–	n/a .	n/a .	Samples	50	0	3.92	2.07846	n/a .	n/a .	100.00 %
786004	Test_Time parameter	–	0.0 sec	n/a .	Samples	50	0	2.83242 sec	0.294025 sec	n/a .	3.21	100.00 %
786006	Testing_Site parameter	–	n/a .	n/a .	Samples	50	0	0	0	n/a .	n/a .	100.00 %
786007	Part_ID parameter	–	n/a .	n/a .	Samples	50	0	25.5	14.5774	n/a .	n/a .	100.00 %

Histogram of Tests

Test	3
Name	Continuity_PPMU1 cs 19.g106
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−638.829 mV
Sigma	0.739011 mV
Range	2.90018 mV
Cp / Cpk	248.1 / 243.0
Samples	50

Test 3: Continuity_PPMU1 cs 19.g106

Test	4
Name	Continuity_PPMU1 p20 19.g128
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−639.957 mV
Sigma	1.16144 mV
Range	4.88389 mV
Cp / Cpk	157.9 / 155.0
Samples	50
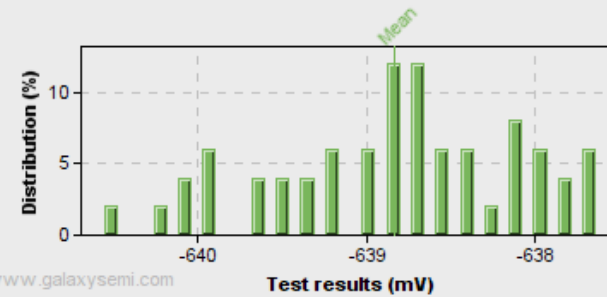
Test 4: Continuity_PPMU1 p20 19.g128
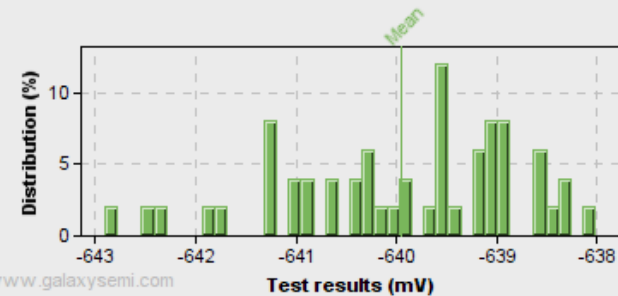
Test	5
Name	Continuity_PPMU1 p21 19.g126
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−639.934 mV
Sigma	1.19625 mV
Range	4.73177 mV
Cp / Cpk	153.3 / 150.5
Samples	50

Test 5: Continuity_PPMU1 p21 19.g126
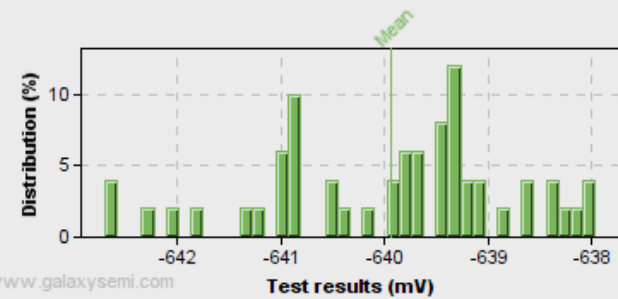
Test	6
Name	Continuity_PPMU1 p22 19.e126
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−639.959 mV
Sigma	1.1051 mV
Range	4.57776 mV
Cp / Cpk	165.9 / 162.9
Samples	50

Test 6: Continuity_PPMU1 p22 19.e126

Histogram of Tests
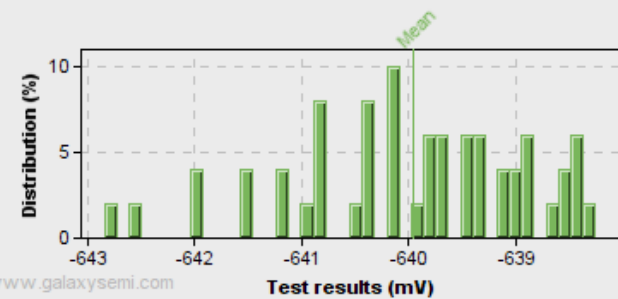
Test	7
Name	Continuity_PPMU1 p23 19.e124
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−639.919 mV
Sigma	1.04921 mV
Range	4.27353 mV
Cp / Cpk	174.7 / 171.5
Samples	50

Test 7: Continuity_PPMU1 p23 19.e124
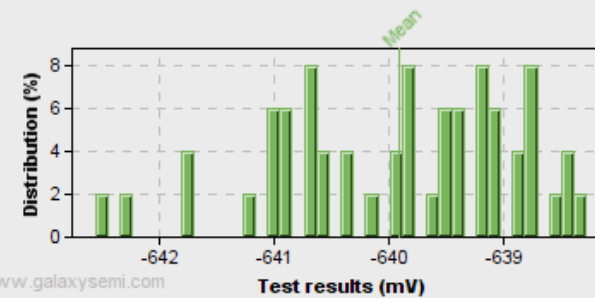
Test	8
Name	Continuity_PPMU1 p40 19.e130
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−640.506 mV
Sigma	1.31771 mV
Range	5.036 mV
Cp / Cpk	139.1 / 136.7
Samples	50

Test 8: Continuity_PPMU1 p40 19.e130
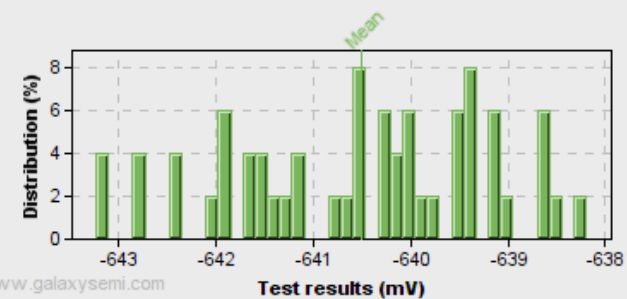
Test	9
Name	Continuity_PPMU1 p41 19.e139
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−640.653 mV
Sigma	1.33769 mV
Range	5.49453 mV
Cp / Cpk	137.1 / 134.7
Samples	50

Test 9: Continuity_PPMU1 p41 19.e139
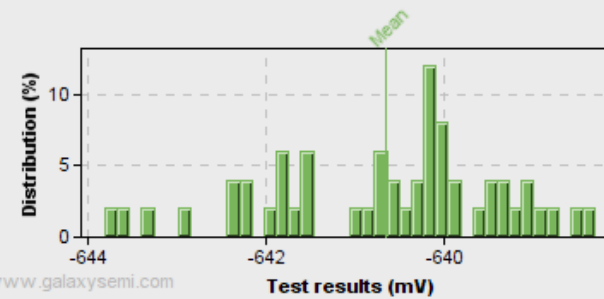
Test	10
Name	Continuity_PPMU1 p42 19.e147
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−640.843 mV
Sigma	1.15966 mV
Range	3.81505 mV
Cp / Cpk	158.1 / 155.5
Samples	50

Test 10: Continuity_PPMU1 p42 19.e147

Histogram of Tests
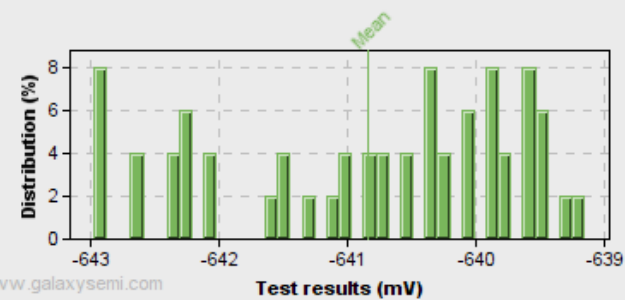
Test	11
Name	Continuity_PPMU1 p43 19.e151
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−640.422 mV
Sigma	1.26161 mV
Range	5.03945 mV
Cp / Cpk	145.3 / 142.8
Samples	50

Test 11: Continuity_PPMU1 p43 19.e151
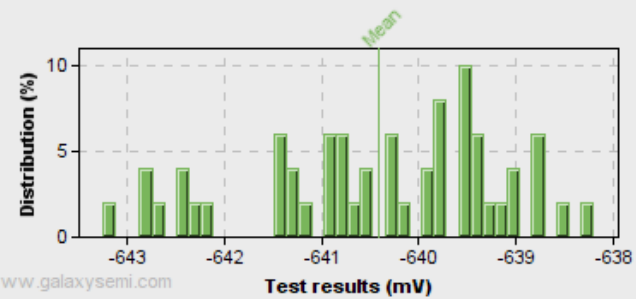
Test	12
Name	Continuity_PPMU1 p50 19.e128
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−639.927 mV
Sigma	1.26847 mV
Range	5.34397 mV
Cp / Cpk	144.5 / 141.9
Samples	50

Test 12: Continuity_PPMU1 p50 19.e128
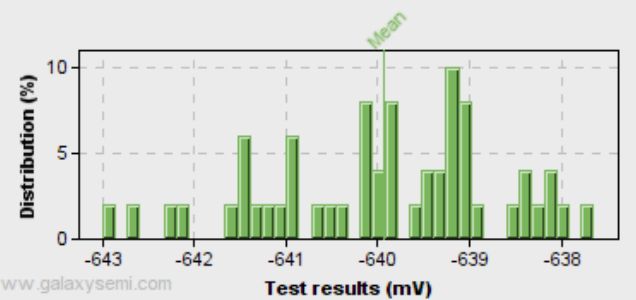
Test	13
Name	Continuity_PPMU1 p51 19.g149
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−636.727 mV
Sigma	0.591955 mV
Range	2.28912 mV
Cp / Cpk	309.7 / 302.2
Samples	50

Test 13: Continuity_PPMU1 p51 19.g149
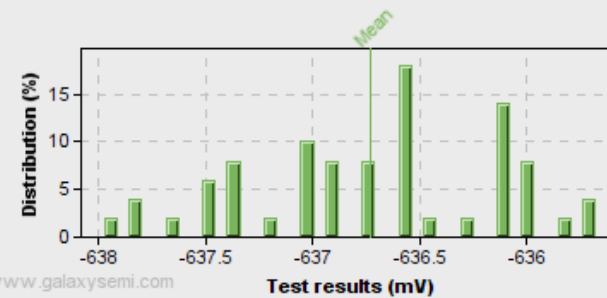
Test	14
Name	Continuity_PPMU1 p52 19.e137
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−638.425 mV
Sigma	1.29891 mV
Range	5.19043 mV
Cp / Cpk	141.1 / 138.2
Samples	50

Test 14: Continuity_PPMU1 p52 19.e137
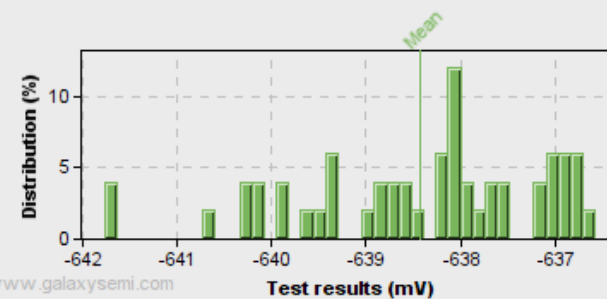
Test	15
Name	Continuity_PPMU1 p53 19.e135
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−638.366 mV
Sigma	1.30317 mV
Range	5.49322 mV
Cp / Cpk	140.7 / 137.7
Samples	50

Test 15: Continuity_PPMU1 p53 19.e135

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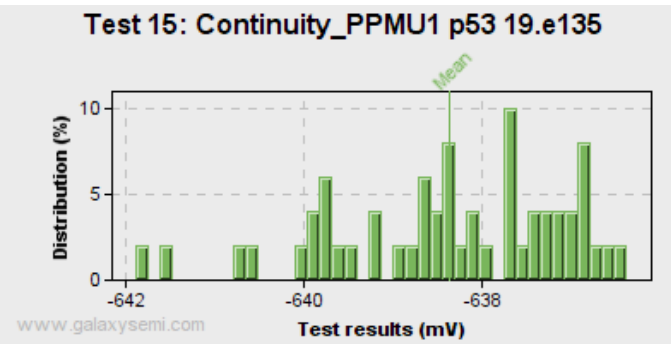
Test	16
Name	Continuity_PPMU1 p60 19.g130
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−638.001 mV
Sigma	1.37306 mV
Range	5.64736 mV
Cp / Cpk	133.5 / 130.6
Samples	50

Test 16: Continuity_PPMU1 p60 19.g130

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Histogram of Tests
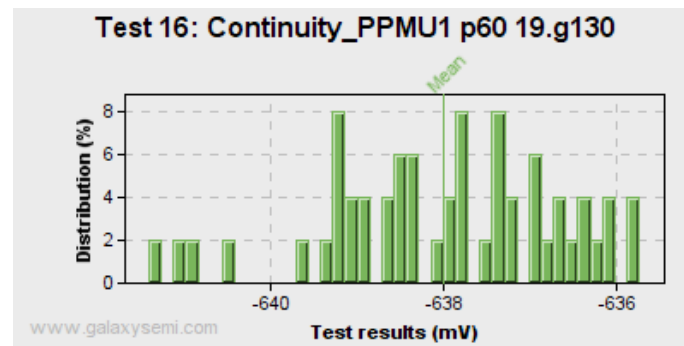
Test	17
Name	Continuity_PPMU1 p61 19.g104
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−637.976 mV
Sigma	1.15666 mV
Range	4.57853 mV
Cp / Cpk	158.5 / 155.0
Samples	50

Test 17: Continuity_PPMU1 p61 19.g104
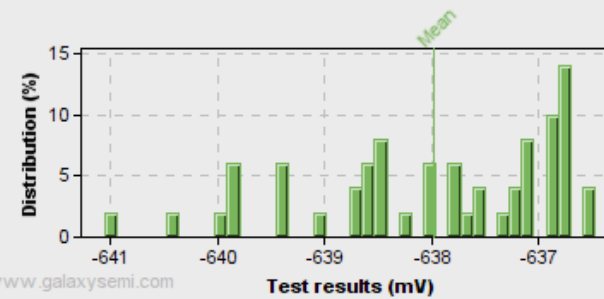
Test	18
Name	Continuity_PPMU1 p62 19.g102
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−637.975 mV
Sigma	1.14359 mV
Range	4.27324 mV
Cp / Cpk	160.3 / 156.8
Samples	50

Test 18: Continuity_PPMU1 p62 19.g102
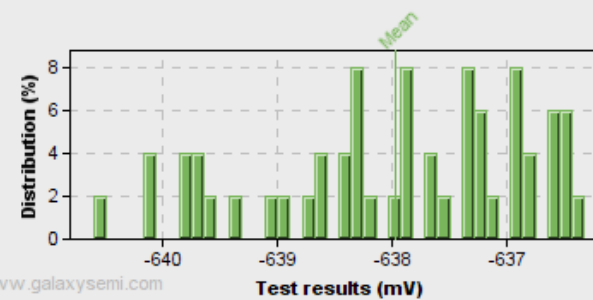
Test	19
Name	Continuity_PPMU1 p63 19.e102
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−637.907 mV
Sigma	1.04194 mV
Range	4.42493 mV
Cp / Cpk	176.0 / 172.1
Samples	50

Test 19: Continuity_PPMU1 p63 19.e102
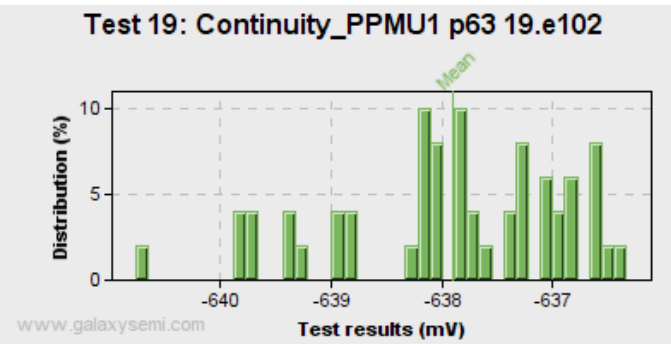
Test	20
Name	Continuity_PPMU1 p70 19.g139
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−640.186 mV
Sigma	1.3308 mV
Range	5.49555 mV
Cp / Cpk	137.8 / 135.3
Samples	50

Test 20: Continuity_PPMU1 p70 19.g139

Histogram of Tests
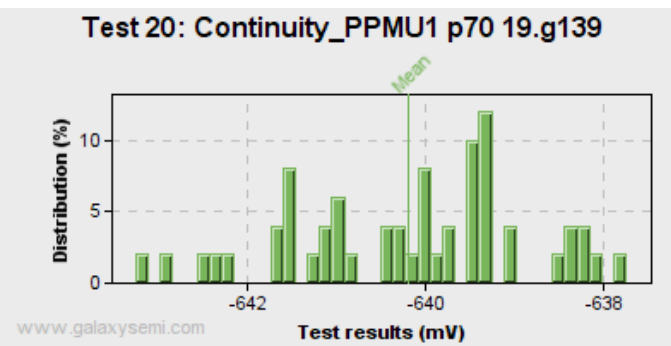
Test	21
Name	Continuity_PPMU1 p71 19.g147
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−638.457 mV
Sigma	1.2443 mV
Range	4.88466 mV
Cp / Cpk	147.3 / 144.2
Samples	50

Test 21: Continuity_PPMU1 p71 19.g147
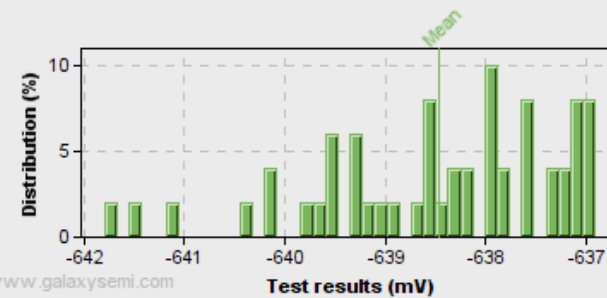
Test	22
Name	Continuity_PPMU1 p72 19.e104
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−637.939 mV
Sigma	0.945071 mV
Range	4.27461 mV
Cp / Cpk	194.0 / 189.7
Samples	50

Test 22: Continuity_PPMU1 p72 19.e104

Histogram of Tests
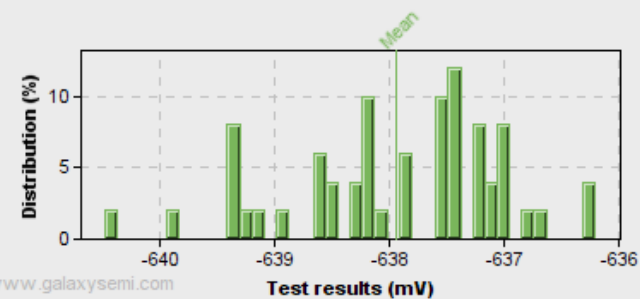
| Test	23
Name	Continuity_PPMU1 p73 19.e108
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−637.672 mV
Sigma	1.03732 mV
Range	4.27294 mV
Cp / Cpk	176.7 / 172.8
Samples	50

Test 23: Continuity_PPMU1 p73 19.e108
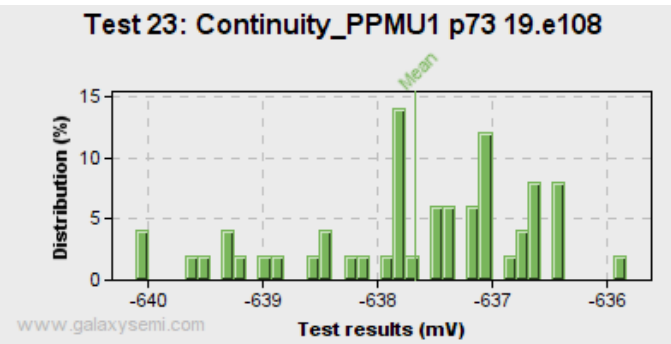
Test	24
Name	Continuity_PPMU1 prog 19.g124
Test type	Parametric
Low limit	−1200 mV
High limit	−100 mV
Exec / Fails	50 / 0 (0.00%)
Mean	−640.068 mV
Sigma	0.916834 mV
Range	3.66259 mV
Cp / Cpk	200.0 / 196.4
Samples	50

Test 24: Continuity_PPMU1 prog 19.g124

Histogram of Tests
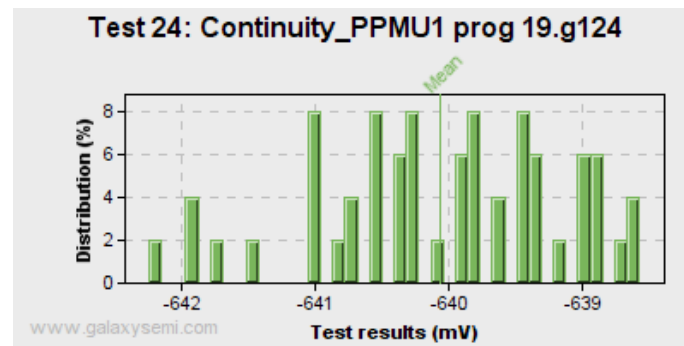
Test	25
Name	SeqLeakage1 p20 19.g128
Test type	Parametric
Low limit	−30 uA
High limit	10 uA
Exec / Fails	50 / 0 (0.00%)
Mean	−0.659074 uA
Sigma	0.0257602 uA
Range	0.0990997 uA
Cp / Cpk	258.8 / 137.9
Samples	50
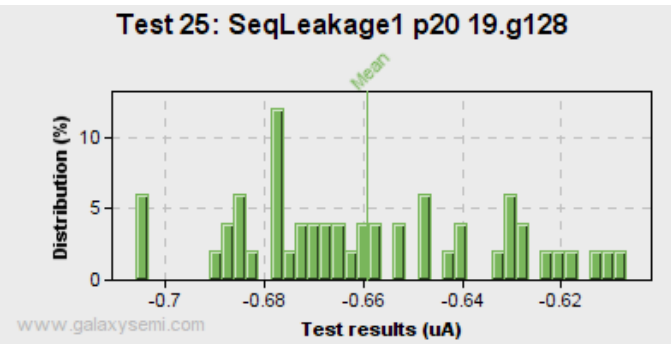
Test	26
Name	SeqLeakage1 p21 19.g126
Test type	Parametric
Low limit	−30 uA
High limit	10 uA
Exec / Fails	50 / 0 (0.00%)
Mean	−0.659128 uA
Sigma	0.0273613 uA
Range	0.104125 uA
Cp / Cpk	243.7 / 129.9
Samples	50

Histogram of Tests
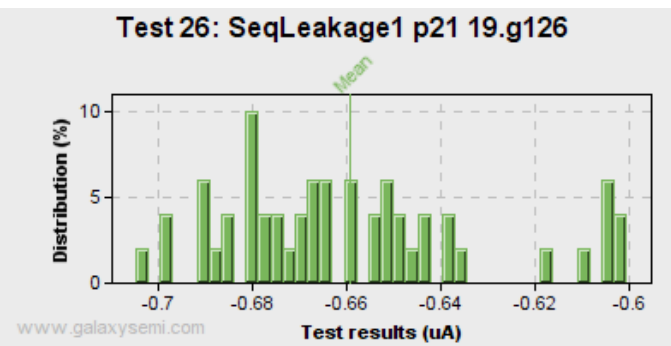
Test	27
Name	SeqLeakage1 p22 19.e126
Test type	Parametric
Low limit	−30 uA
High limit	10 uA
Exec / Fails	50 / 0 (0.00%)
Mean	−0.659499 uA
Sigma	0.0238835 uA
Range	0.0941441 uA
Cp / Cpk	279.1 / 148.8
Samples	50

Test 27: SeqLeakage1 p22 19.e126
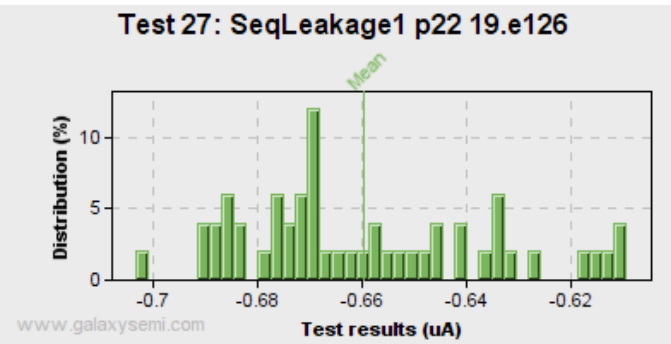
Test	28
Name	SeqLeakage1 p23 19.e124
Test type	Parametric
Low limit	−30 uA
High limit	10 uA
Exec / Fails	50 / 0 (0.00%)
Mean	−0.662982 uA
Sigma	0.0224599 uA
Range	0.0915531 uA
Cp / Cpk	296.8 / 158.3
Samples	50

Test 28: SeqLeakage1 p23 19.e124

Histogram of Tests
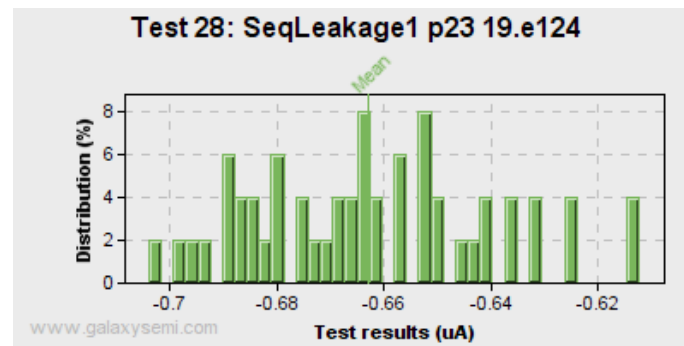
Test	29
Name	SeqLeakage2 cs 19.g106
Test type	Parametric
Low limit	−30 uA
High limit	10 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00442263 uA
Sigma	0.00836942 uA
Range	0.042849 uA
Cp / Cpk	796.6 / 398.1
Samples	50
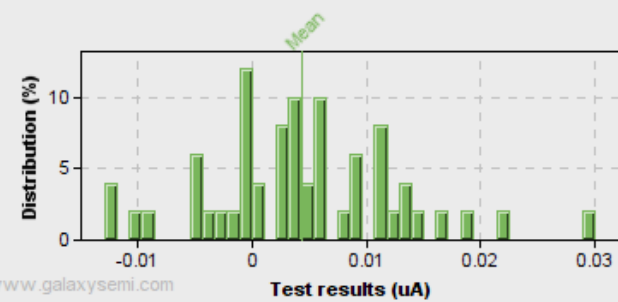
Test	30
Name	SeqLeakage2 prog 19.g124
Test type	Parametric
Low limit	−30 uA
High limit	10 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.0017725 uA
Sigma	0.0110325 uA
Range	0.0542445 uA
Cp / Cpk	604.3 / 302.1
Samples	50
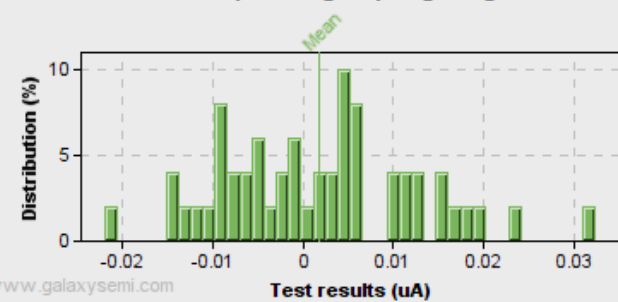
Test	31
Name	VBT_outpleakage1 p40 19.e130
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	−0.000566971 uA
Sigma	0.0114804 uA
Range	0.0635926 uA
Cp / Cpk	435.5 / 290.3
Samples	50

Test 31: VBT_outpleakage1 p40 19.e130
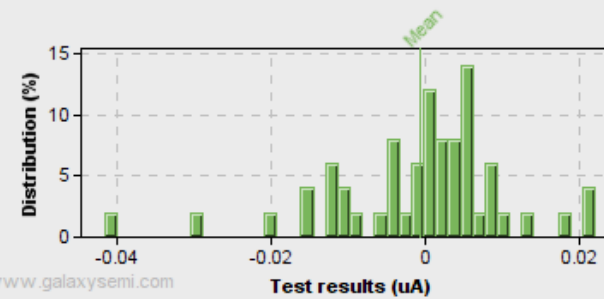
Test	32
Name	VBT_outpleakage1 p41 19.e139
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.000428692 uA
Sigma	0.00803862 uA
Range	0.035214 uA
Cp / Cpk	622.0 / 414.7
Samples	50

Test 32: VBT_outpleakage1 p41 19.e139
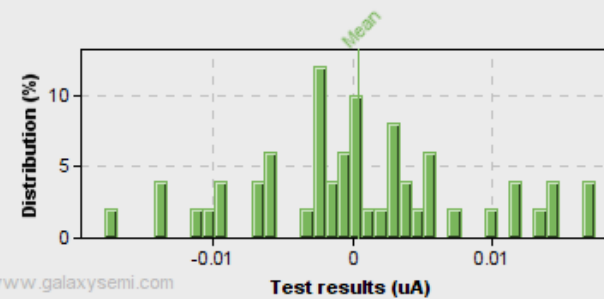
Test	33
Name	VBT_outpleakage1 p42 19.e147
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.0015068 uA
Sigma	0.0102733 uA
Range	0.0479436 uA
Cp / Cpk	486.7 / 324.5
Samples	50

Test 33: VBT_outpleakage1 p42 19.e147
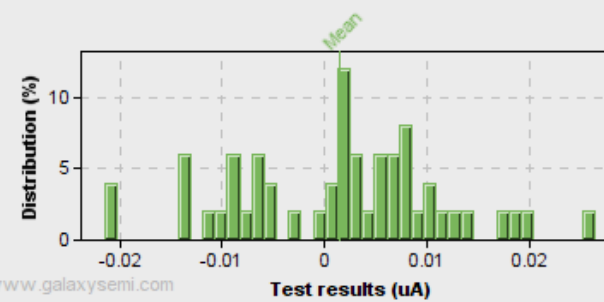
Test	34
Name	VBT_outpleakage1 p43 19.e151
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	−0.00103971 uA
Sigma	0.00867403 uA
Range	0.042047 uA
Cp / Cpk	576.4 / 384.2
Samples	50

Test 34: VBT_outpleakage1 p43 19.e151

Histogram of Tests
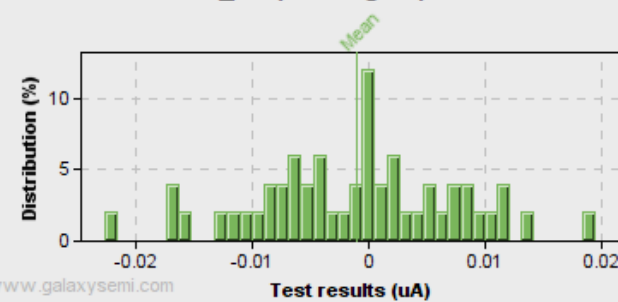
Test	35
Name	VBT_outpleakage1 p50 19.e128
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00120289 uA
Sigma	0.010007 uA
Range	0.0411114 uA
Cp / Cpk	499.6 / 333.1
Samples	50

Test 35: VBT_outpleakage1 p50 19.e128
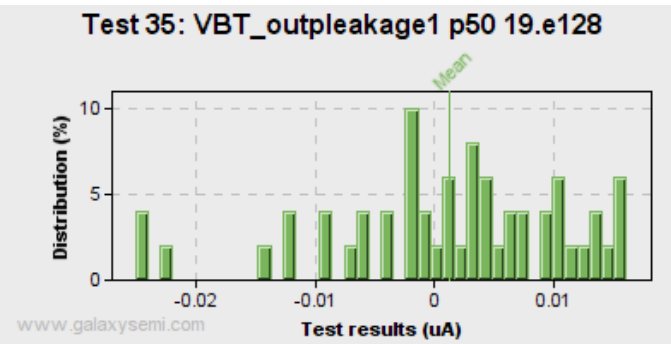
Test	36
Name	VBT_outpleakage1 p51 19.g149
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00202032 uA
Sigma	0.00936446 uA
Range	0.0466815 uA
Cp / Cpk	533.9 / 356.0
Samples	50

Test 36: VBT_outpleakage1 p51 19.g149

Histogram of Tests
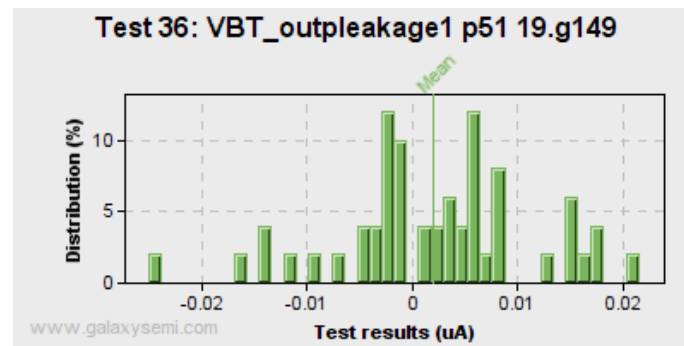
Test	37
Name	VBT_outpleakage1 p52 19.e137
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	−0.00105678 uA
Sigma	0.011461 uA
Range	0.0520731 uA
Cp / Cpk	436.3 / 290.8
Samples	50

Test 37: VBT_outpleakage1 p52 19.e137
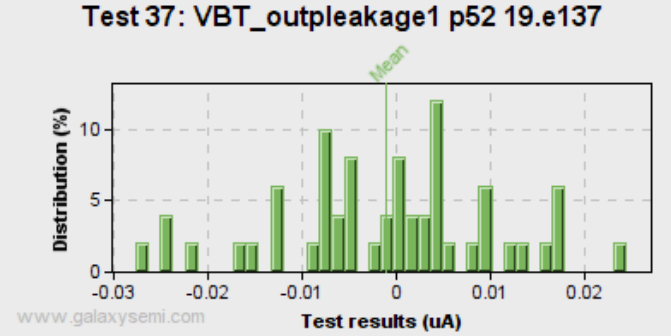
Test	38
Name	VBT_outpleakage1 p53 19.e135
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	−0.00277265 uA
Sigma	0.00892291 uA
Range	0.0380858 uA
Cp / Cpk	560.4 / 373.5
Samples	50

Test 38: VBT_outpleakage1 p53 19.e135

Histogram of Tests
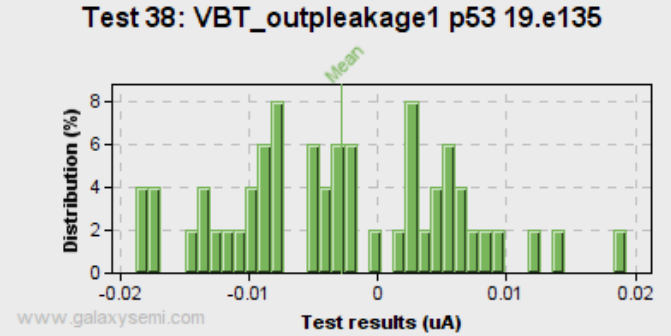
Test	39
Name	VBT_outpleakage1 p60 19.g130
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.000290797 uA
Sigma	0.00921436 uA
Range	0.0466806 uA
Cp / Cpk	542.6 / 361.8
Samples	50

Test 39: VBT_outpleakage1 p60 19.g130
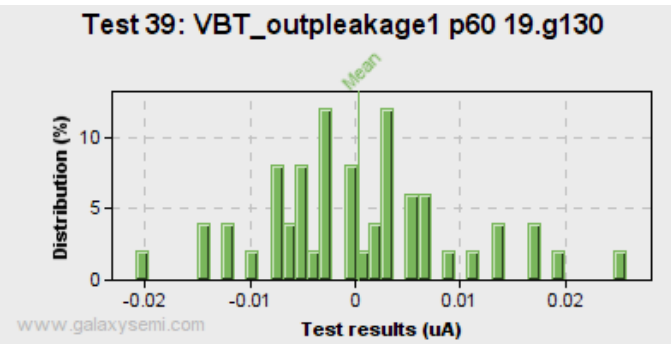
Test	40
Name	VBT_outpleakage1 p61 19.g104
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00413707 uA
Sigma	0.0114122 uA
Range	0.0572473 uA
Cp / Cpk	438.1 / 292.2
Samples	50

Test 40: VBT_outpleakage1 p61 19.g104

Histogram of Tests
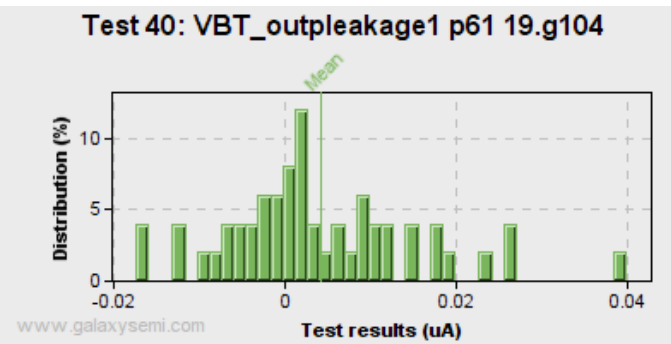
Test	41
Name	VBT_outpleakage1 p62 19.g102
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00719384 uA
Sigma	0.0160235 uA
Range	0.109438 uA
Cp / Cpk	312.0 / 208.2
Samples	50

Test 41: VBT_outpleakage1 p62 19.g102
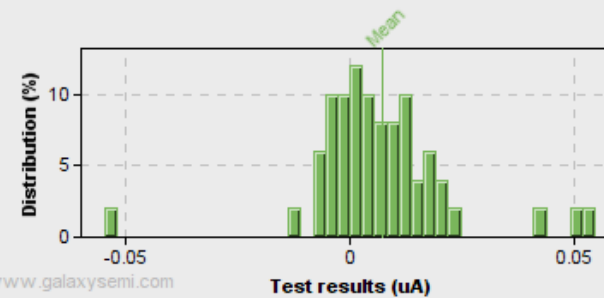
Test	42
Name	VBT_outpleakage1 p63 19.e102
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00176909 uA
Sigma	0.00954362 uA
Range	0.0449897 uA
Cp / Cpk	523.9 / 349.3
Samples	50

Test 42: VBT_outpleakage1 p63 19.e102

Histogram of Tests
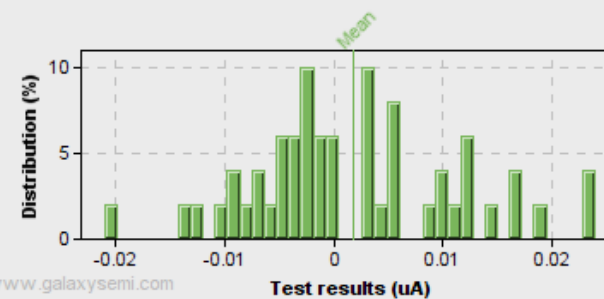
Test	43
Name	VBT_outpleakage1 p70 19.g139
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	−0.00163175 uA
Sigma	0.00925232 uA
Range	0.0365999 uA
Cp / Cpk	540.4 / 360.2
Samples	50

Test 43: VBT_outpleakage1 p70 19.g139
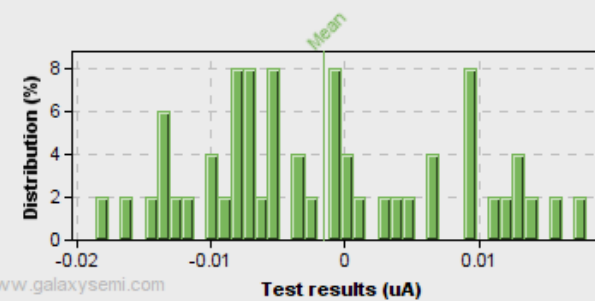
Test	44
Name	VBT_outpleakage1 p71 19.g147
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00596628 uA
Sigma	0.00833879 uA
Range	0.0406443 uA
Cp / Cpk	599.6 / 400.0
Samples	50

Test 44: VBT_outpleakage1 p71 19.g147

Histogram of Tests
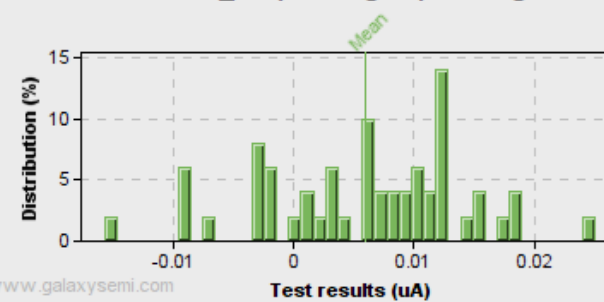
Test	45
Name	VBT_outpleakage1 p72 19.e104
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	−0.00100623 uA
Sigma	0.011639 uA
Range	0.0472625 uA
Cp / Cpk	429.6 / 286.4
Samples	50

Test 45: VBT_outpleakage1 p72 19.e104
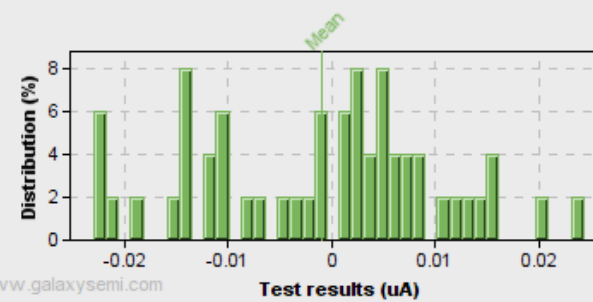
Test	46
Name	VBT_outpleakage1 p73 19.e108
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00117388 uA
Sigma	0.0113674 uA
Range	0.0640296 uA
Cp / Cpk	439.9 / 293.3
Samples	50

Test 46: VBT_outpleakage1 p73 19.e108

Histogram of Tests
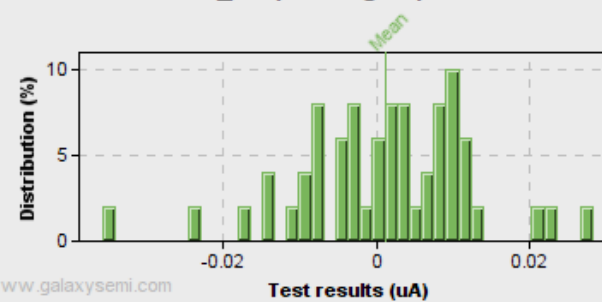
Test	47
Name	OutputZ_leak_vbt1 p40 19.e130
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	−0.00107265 uA
Sigma	0.0102458 uA
Range	0.0452044 uA
Cp / Cpk	488.0 / 325.3
Samples	50

Test 47: OutputZ_leak_vbt1 p40 19.e130
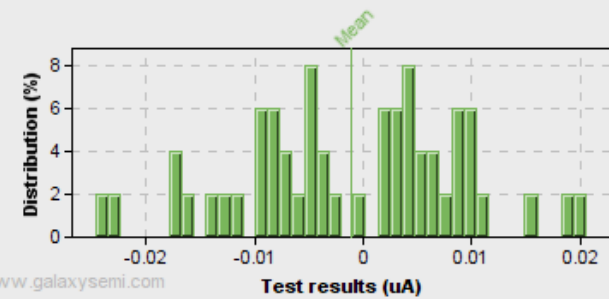
Test	48
Name	OutputZ_leak_vbt1 p41 19.e139
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00174539 uA
Sigma	0.008824 uA
Range	0.0398071 uA
Cp / Cpk	566.6 / 377.8
Samples	50

Test 48: OutputZ_leak_vbt1 p41 19.e139
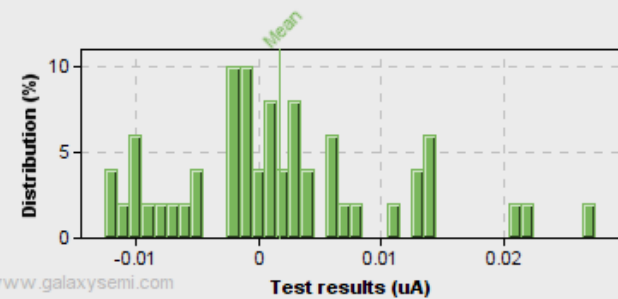
Test	49
Name	OutputZ_leak_vbt1 p42 19.e147
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.000867551 uA
Sigma	0.00898146 uA
Range	0.0357674 uA
Cp / Cpk	556.7 / 371.2
Samples	50

Test 49: OutputZ_leak_vbt1 p42 19.e147
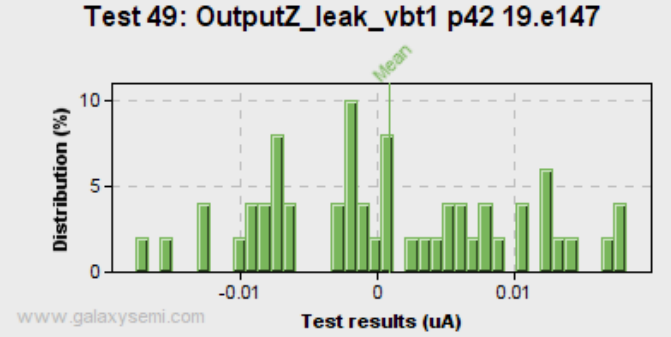
Test	50
Name	OutputZ_leak_vbt1 p43 19.e151
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00211 uA
Sigma	0.0095082 uA
Range	0.0443405 uA
Cp / Cpk	525.9 / 350.6
Samples	50

Test 50: OutputZ_leak_vbt1 p43 19.e151

Histogram of Tests
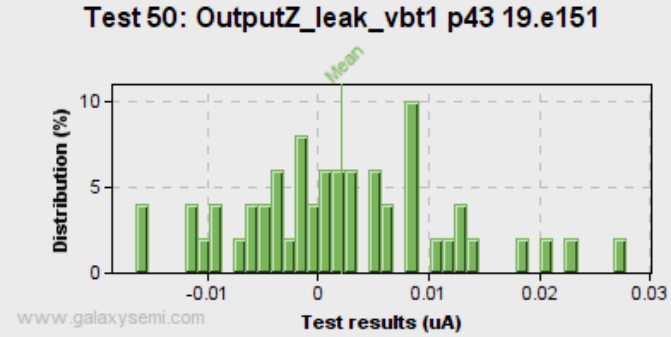
Test	51
Name	OutputZ_leak_vbt1 p50 19.e128
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00216216 uA
Sigma	0.00949243 uA
Range	0.0365435 uA
Cp / Cpk	526.7 / 351.2
Samples	50

Test 51: OutputZ_leak_vbt1 p50 19.e128
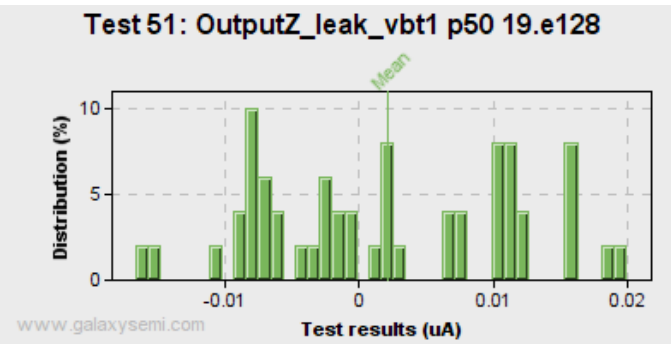
Test	52
Name	OutputZ_leak_vbt1 p51 19.g149
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00180604 uA
Sigma	0.00824136 uA
Range	0.0382635 uA
Cp / Cpk	606.7 / 404.5
Samples	50

Test 52: OutputZ_leak_vbt1 p51 19.g149

Histogram of Tests
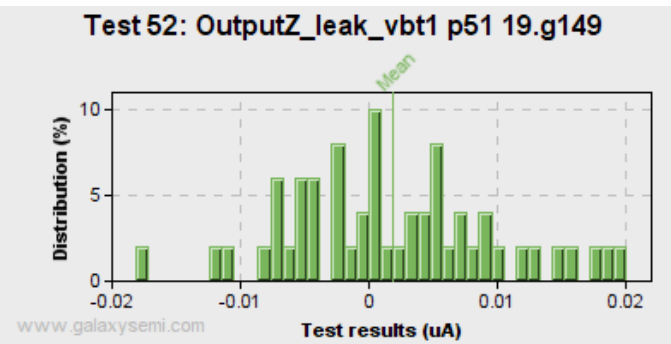
Test	53
Name	OutputZ_leak_vbt1 p52 19.e137
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00125588 uA
Sigma	0.00863721 uA
Range	0.0451811 uA
Cp / Cpk	578.9 / 386.0
Samples	50
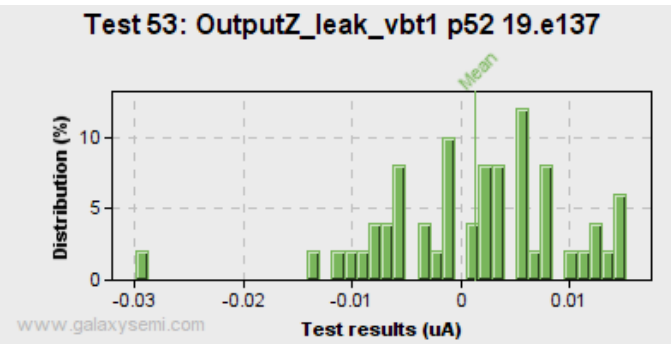
Test	54
Name	OutputZ_leak_vbt1 p53 19.e135
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	−0.0024832 uA
Sigma	0.00997394 uA
Range	0.0479882 uA
Cp / Cpk	501.3 / 334.1
Samples	50

Histogram of Tests
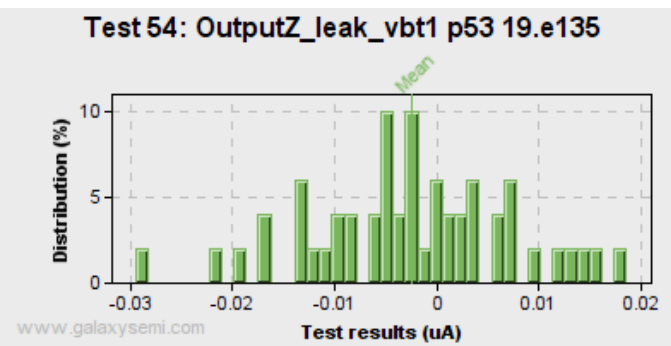
Test	55
Name	OutputZ_leak_vbt1 p60 19.g130
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	−0.000566289 uA
Sigma	0.00868435 uA
Range	0.0367323 uA
Cp / Cpk	575.7 / 383.8
Samples	50
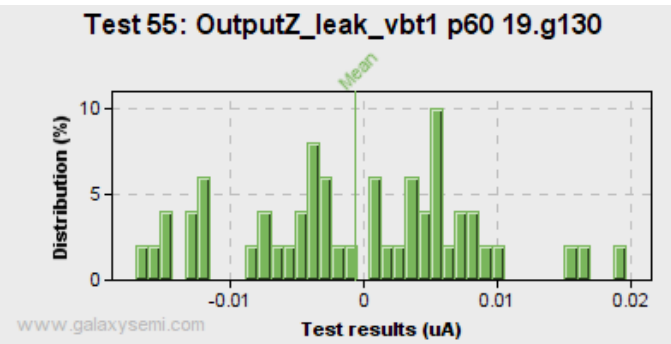
Test	56
Name	OutputZ_leak_vbt1 p61 19.g104
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00305319 uA
Sigma	0.0096245 uA
Range	0.035875 uA
Cp / Cpk	519.5 / 346.4
Samples	50

Histogram of Tests
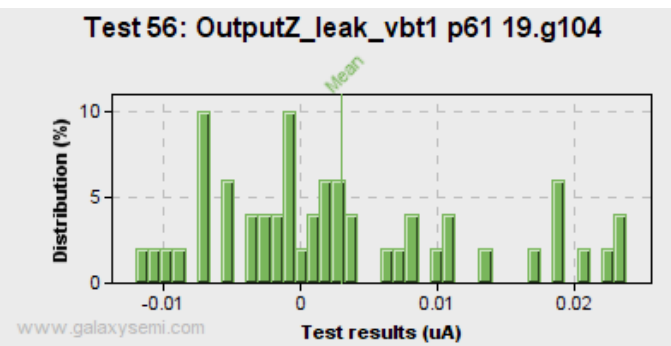
Test	57
Name	OutputZ_leak_vbt1 p62 19.g102
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00472956 uA
Sigma	0.00829177 uA
Range	0.0443875 uA
Cp / Cpk	603.0 / 402.2
Samples	50

Test 57: OutputZ_leak_vbt1 p62 19.g102
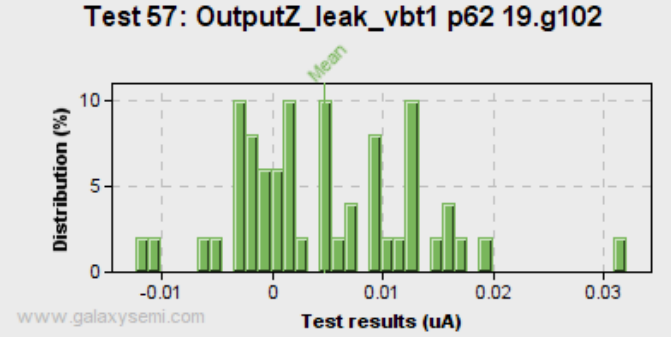
Test	58
Name	OutputZ_leak_vbt1 p63 19.e102
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	−0.000228761 uA
Sigma	0.0106321 uA
Range	0.05109 uA
Cp / Cpk	470.3 / 313.5
Samples	50

Test 58: OutputZ_leak_vbt1 p63 19.e102

Histogram of Tests
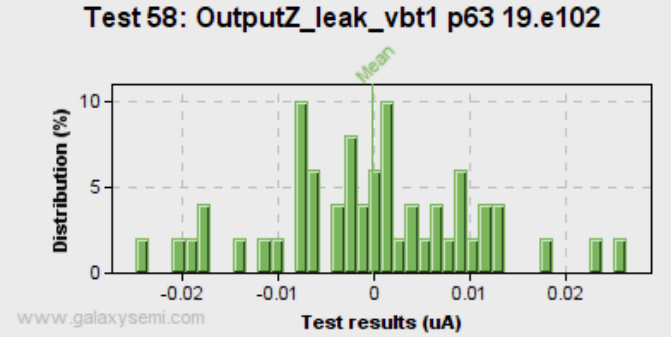
Test	59
Name	OutputZ_leak_vbt1 p70 19.g139
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	−0.00215024 uA
Sigma	0.00756443 uA
Range	0.0457499 uA
Cp / Cpk	661.0 / 440.6
Samples	50

Test 59: OutputZ_leak_vbt1 p70 19.g139
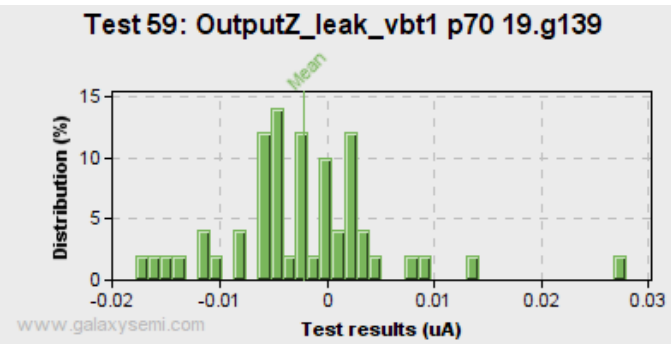
Test	60
Name	OutputZ_leak_vbt1 p71 19.g147
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00279142 uA
Sigma	0.0116121 uA
Range	0.0536812 uA
Cp / Cpk	430.6 / 287.1
Samples	50

Test 60: OutputZ_leak_vbt1 p71 19.g147

Histogram of Tests
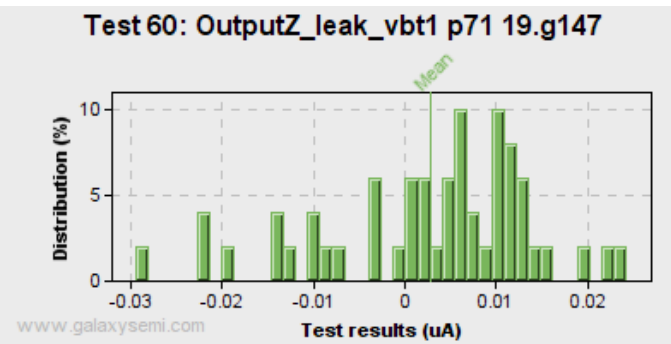
Test	61
Name	OutputZ_leak_vbt1 p72 19.e104
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.000213443 uA
Sigma	0.010307 uA
Range	0.0449756 uA
Cp / Cpk	485.1 / 323.4
Samples	50
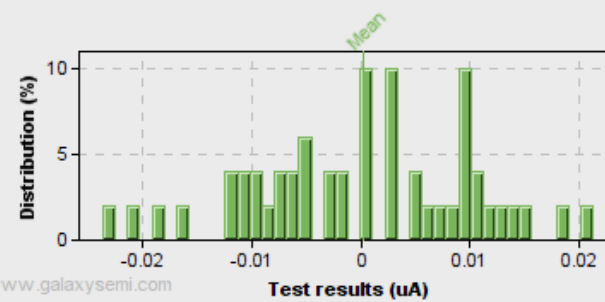
Test	62
Name	OutputZ_leak_vbt1 p73 19.e108
Test type	Parametric
Low limit	−10 uA
High limit	20 uA
Exec / Fails	50 / 0 (0.00%)
Mean	0.00324722 uA
Sigma	0.00959745 uA
Range	0.0472599 uA
Cp / Cpk	521.0 / 347.4
Samples	50

Histogram of Tests
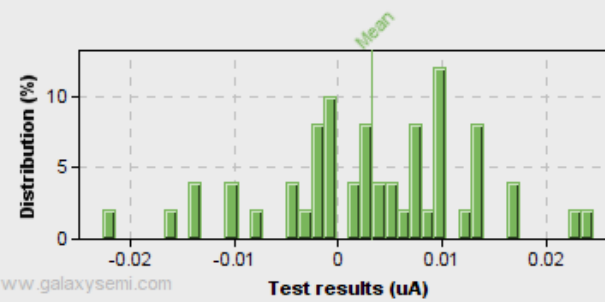
Test	64
Name	icc_static_vbt11 vcc 15.e201 <> Icc_static
Test type	Parametric
Low limit	10 uA
High limit	500 uA
Exec / Fails	50 / 0 (0.00%)
Mean	21.2436 uA
Sigma	0.217199 uA
Range	1.1158 uA
Cp / Cpk	376.0 / 17.26
Samples	50

Test 64: icc_static_vbt11 vcc 15.e201 <> Icc_static
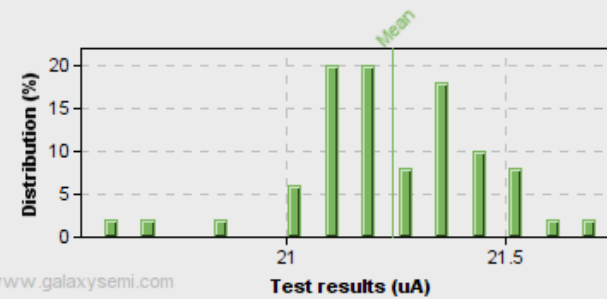
Test	65
Name	Icc_dynamic vcc 15.e201 <> Icc_dynamic
Test type	Parametric
Low limit	10 uA
High limit	500 uA
Exec / Fails	50 / 0 (0.00%)
Mean	20.7699 uA
Sigma	0.419498 uA
Range	2.91824 uA
Cp / Cpk	194.7 / 8.56
Samples	50

Test 65: Icc_dynamic vcc 15.e201 <> Icc_dynamic

Histogram of Tests
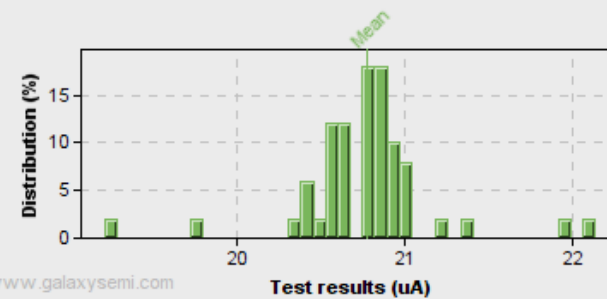
Test	67
Name	func_T5 p50 19.e128
Test type	Parametric
Low limit	n/a .
High limit	n/a .
Exec / Fails	50 / 0 (0.00%)
Mean	0.14524
Sigma	0.00239523
Range	0.01
Cp / Cpk	n/a . / n/a .
Samples	50

Test 67: func_T5 p50 19.e128
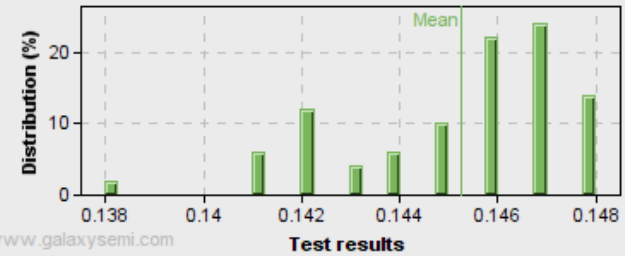
Test	68
Name	func_T5 p50 19.e128
Test type	Parametric
Low limit	n/a .
High limit	n/a .
Exec / Fails	50 / 0 (0.00%)
Mean	3.28306
Sigma	0.00186714
Range	0.00699997
Cp / Cpk	n/a . / n/a .
Samples	50

Test 68: func_T5 p50 19.e128

Histogram of Tests
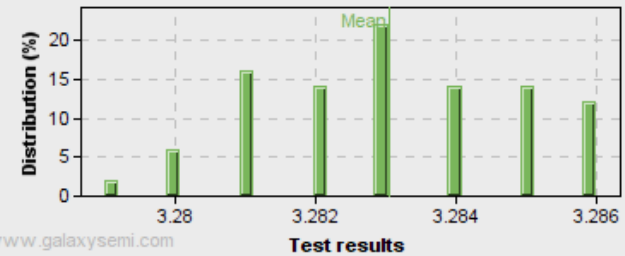
Test	71
Name	func_T6 p50 19.e128
Test type	Parametric
Low limit	150 ns
High limit	350 ns
Exec / Fails	50 / 0 (0.00%)
Mean	231.072 ns
Sigma	0.883186 ns
Range	3.60001 ns
Cp / Cpk	37.74 / 30.60
Samples	50

Test 71: func_T6 p50 19.e128
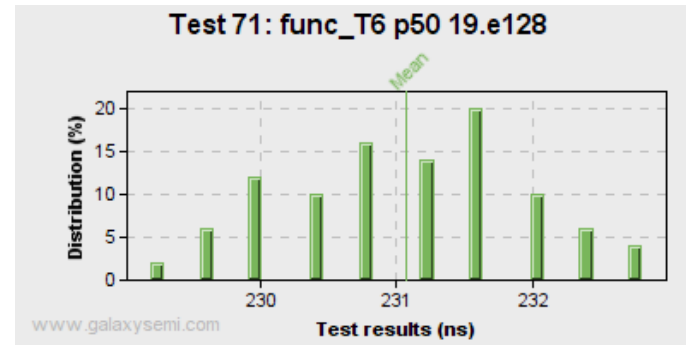
Test	72
Name	func_T6 p50 19.e128
Test type	Parametric
Low limit	150 ns
High limit	350 ns
Exec / Fails	50 / 0 (0.00%)
Mean	246.928 ns
Sigma	0.813919 ns
Range	3.2 ns
Cp / Cpk	40.95 / 39.70
Samples	50

Test 72: func_T6 p50 19.e128

Histogram of Tests
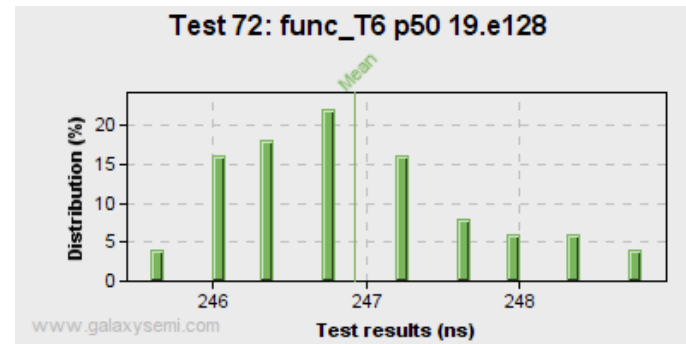
Test	73
Name	func_T6 A8 0
Test type	Parametric
Low limit	1 ns
High limit	100 ns
Exec / Fails	50 / 0 (0.00%)
Mean	15.856 ns
Sigma	1.14503 ns
Range	5.2 ns
Cp / Cpk	14.41 / 4.32
Samples	50

Test 73: func_T6 A8 0
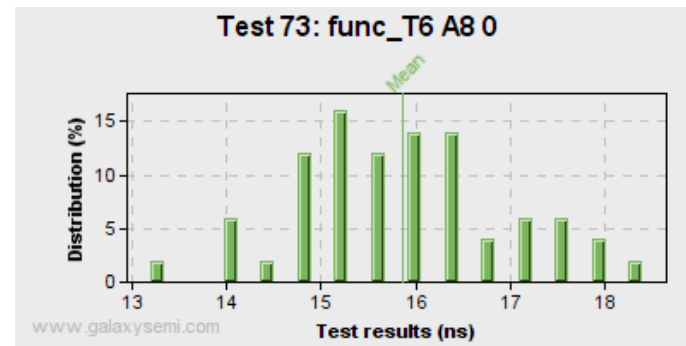
Test	75
Name	func_T7 p53 19.e135
Test type	Parametric
Low limit	n/a .
High limit	n/a .
Exec / Fails	50 / 0 (0.00%)
Mean	3.28332 V
Sigma	0.00218942 V
Range	0.00900006 V
Cp / Cpk	n/a . / n/a .
Samples	50

Test 75: func_T7 p53 19.e135

Histogram of Tests
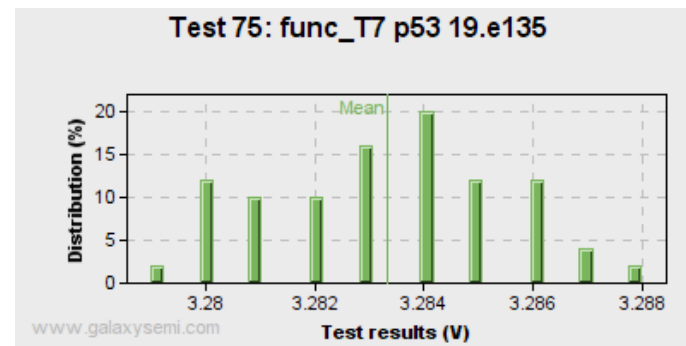
Test	76
Name	func_T7 p53 19.e135
Test type	Parametric
Low limit	n/a .
High limit	n/a .
Exec / Fails	50 / 0 (0.00%)
Mean	0.13898
Sigma	0.00240314
Range	0.009
Cp / Cpk	n/a . / n/a .
Samples	50

Test 76: func_T7 p53 19.e135
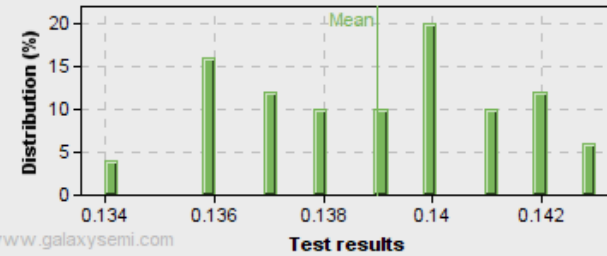
Test	81
Name	func_T8 A8 0
Test type	Parametric
Low limit	1 ns
High limit	20 ns
Exec / Fails	50 / 0 (0.00%)
Mean	9.216 ns
Sigma	1.58865 ns
Range	7.8 ns
Cp / Cpk	1.99 / 1.72
Samples	50

Test 81: func_T8 A8 0

Histogram of Tests
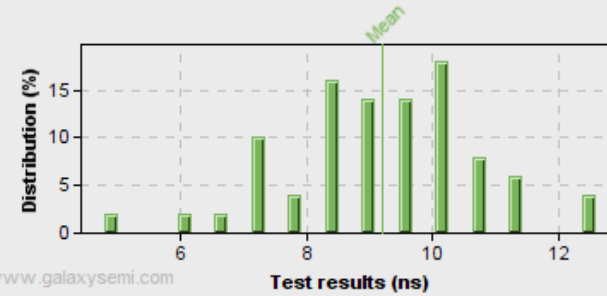
Test	786000
Name	Soft_Bin parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	50 / 0 (0.00%)
Mean	1
Sigma	0
Range	0
Cp / Cpk	n/a . / n/a .
Samples	50

Test 786000: Soft_Bin parameter
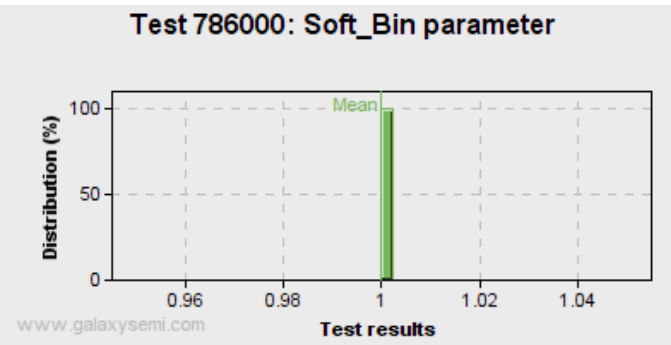
Test	786001
Name	Hard_Bin parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	50 / 0 (0.00%)
Mean	1
Sigma	0
Range	0
Cp / Cpk	n/a . / n/a .
Samples	50

Test 786001: Hard_Bin parameter

Histogram of Tests
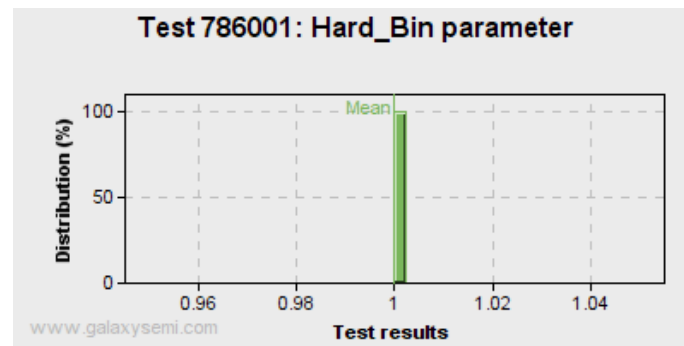
Test	786002
Name	Die_X parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	50 / 0 (0.00%)
Mean	2.94
Sigma	2.0445
Range	6
Cp / Cpk	n/a . / n/a .
Samples	50

Test 786002: Die_X parameter
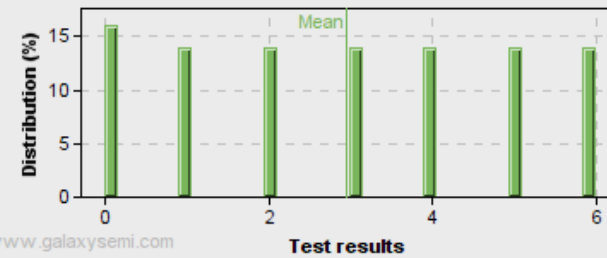
Test	786003
Name	Die_Y parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	50 / 0 (0.00%)
Mean	3.92
Sigma	2.07846
Range	7
Cp / Cpk	n/a . / n/a .
Samples	50

Test 786003: Die_Y parameter

Histogram of Tests
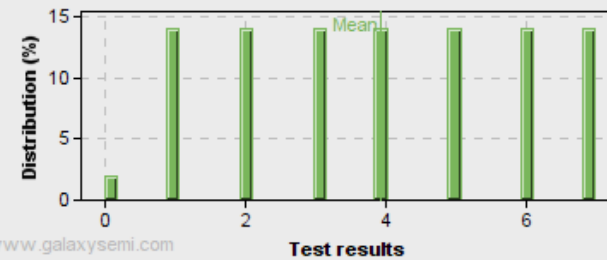
Test	786004
Name	Test_Time parameter
Test type	–
Low limit	0.0 sec
High limit	n/a .
Exec / Fails	50 / 0 (0.00%)
Mean	2.83242 sec
Sigma	0.294025 sec
Range	2.121 sec
Cp / Cpk	n/a . / 3.21
Samples	50

Test 786004: Test_Time parameter
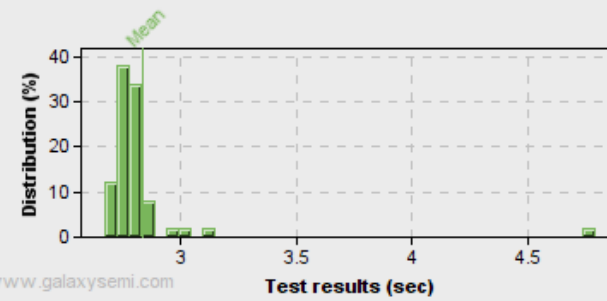
Test	786006
Name	Testing_Site parameter
Test type	–
Low limit	n/a .
High limit	n/a .
Exec / Fails	50 / 0 (0.00%)
Mean	0
Sigma	0
Range	0
Cp / Cpk	n/a . / n/a .
Samples	50

Test 786006: Testing_Site parameter

Histogram of Tests
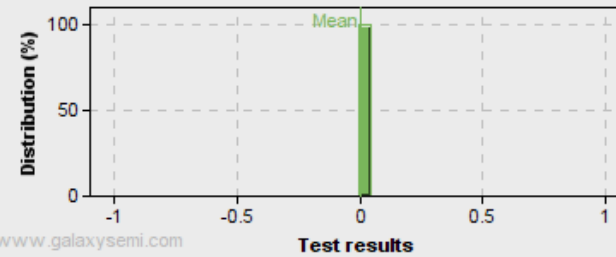
Test		
Test	786007	
Name	Part_ID parameter	
Test type	–	
Low limit	n/a .	
High limit	n/a .	
Exec / Fails	50 / 0 (0.00%)	
Mean	25.5	
Sigma	14.5774	
Range	49	
Cp / Cpk	n/a . / n/a .	
Samples	50	

Test 786007: Part_ID parameter
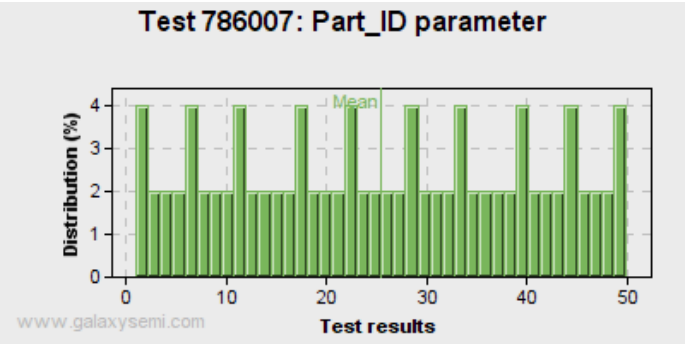
Pareto of Tests Cp

Test	Name	Cp	Test Cp Chart

Shows all Cp <= 1.7 (Defined in Options , section 'Pareto/Define Cp cut−off limit')

Pareto of Tests Cpk

Test	Name	Cpk	Test Cpk Chart

Shows all Cpk <= 1.3 (Defined in Options , section 'Pareto/Define Cp cut−off limit')

Pareto of Tests failures

Test	Name	Failing Bin	Failures count	Yield Loss	Fail contribution	Test Fail rate	Failures Chart
–	**Cumul. of failures**	–	0	0.0 %	0.0 %	0.0 %	

–– Yield loss: number of failed test executions / number of parts

–– Fail contribution: number of failed test executions / number of parts failed

–– Test Fail rate: number of failed test executions / number of test executions

Pareto of Functional Failure Signatures (pins tested in parallel)

Total devices tested: **50**
Total patterns detected: **0**

Fail count	% of failures	% of tested	Functional Failure signatures (tested pins failing together)

Shows first 25 % of the failure signatures (Defined in <u>Options</u>, section 'Pareto/Define Failure Signatures cut−off limit')

No Functional failure signature detected

Possible root cause: The 'Options/Data processing/Multi−results...' option is set to 'merge' instead of 'no merge'

Pareto of Parametric Failure Signatures (tests failing concurrently)

No Parametric failure signature detected

Pareto of Software Bins

Software Binning	Bin Name	Count	Percentage	Software Binning Chart
1	–	50	100.0 %	███████████████████████
Cumul.	**Cumul.**	**50**	**100.0%**	

Pareto of Hardware Bins

Hardware Binning	Bin Name	Count	Percentage	Hardware Binning Chart
1	–	50	100.0 %	
Cumul.	Cumul.	50	100.0%	

Wafermaps & Strip Maps

Map type	Show Software bins
Devices tested (with retests)	50
Total physical parts tested	50 (only applies to Wafermaps)

List of Individual Maps

Top 10 Software Binning	1
Color	
Pass/Fail	P
Percentage	100.0%
Total count	50

Map style	STRIP map (parts tested are PACKAGED DEVICES!)
Total physical parts tested	50
Parts processed	All Data / parts (any Bin)
Data from Sites	All sites
Strip started	Thu Sep 05 04:09:16 2024
Strip ended	Thu Sep 05 04:12:36 2024
Wafer tested in	3 minutes 20 seconds
Average device test time	4.000 sec.
Map dimensions	LowX=0, LowY=0, HighX=6, HighY=7

Die Y locations

0

0

Run 1, Run 2,...
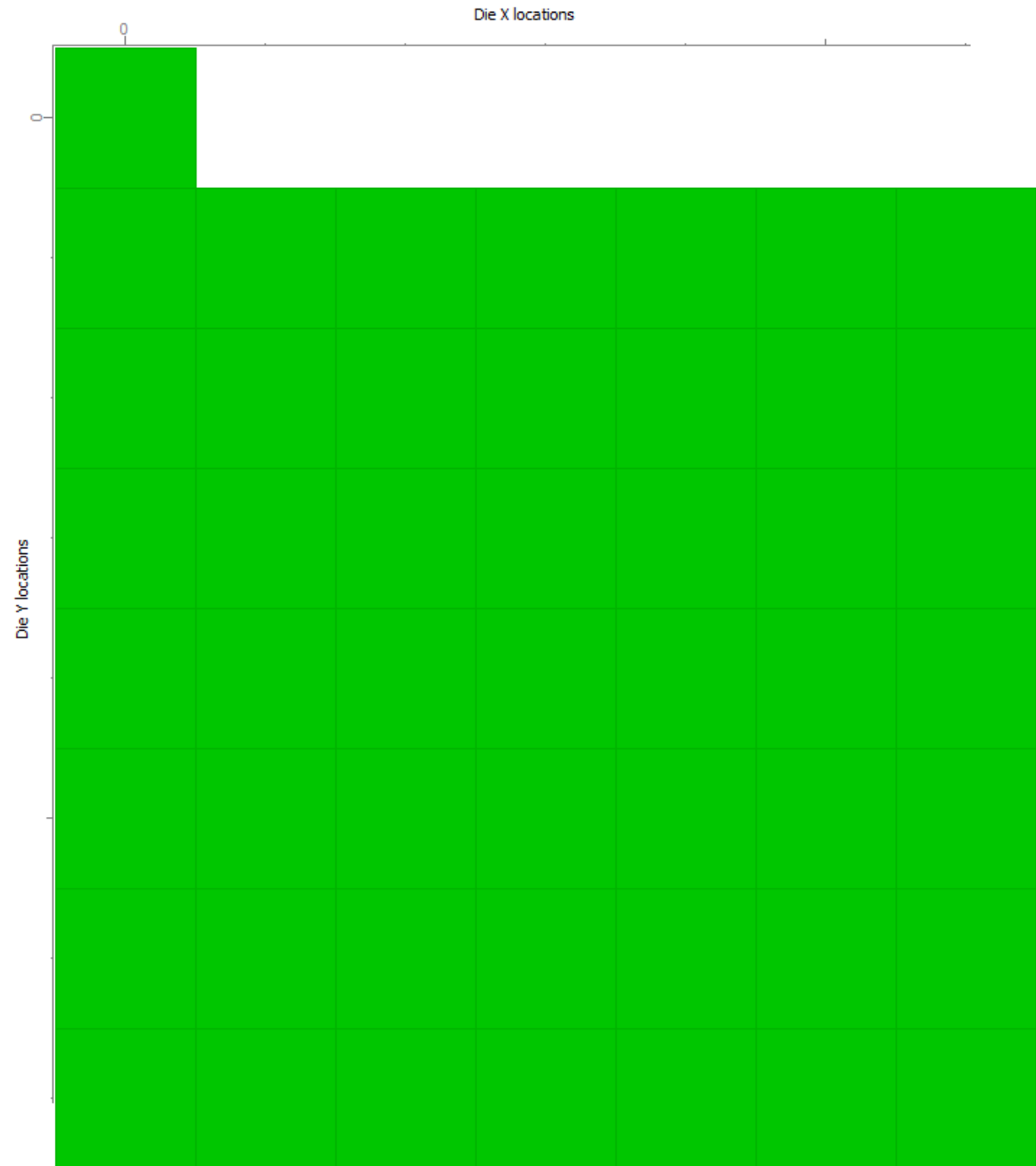
Software Binning Summary

Software Binning	Bin Name	Pass/ Fail	Total count	Percentage	Software Binning Chart
1	–	P	50	100.0 %	
All PASS Bins	**All PASS Bins**	P	**50**	**100.0 %**	
ALL Bins	**ALL Bins**	–	**50**	**100.0 %**	

Hint: From the 'Options' tab in the 'Binning' section, you can configure how to compute the binning (from summary or samples)

Hardware Binning Summary

Hardware Binning	Bin Name	Pass/ Fail	Total count	Percentage	Hardware Binning Chart
1	–	P	50	100.0 %	
All PASS Bins	All PASS Bins	P	50	100.0 %	
ALL Bins	ALL Bins	–	50	100.0 %	

Hint: From the 'Options' tab in the 'Binning' section, you can configure how to compute the binning (from summary or samples)

Message Log

No log message to report

Global Information

Report from	Teradyne–Examinator–Pro+ – V8.1.5 – www.galaxysemi.com
Report created	Wed Sep 04 16:13:25 2024
Data processed	298.1 KB (305204 bytes)
Processing time	0.87 second
Processing speed	350.4 KB/sec
Examinator expires	Sun Sep 3 2034
(null)	–
File name	C:/Users/rahmana/OneDrive – Teradyne/Desktop/New Hire/New Hire Tech/UFP New Hire Train/Project 1/i8243/online/results_notempv1_50loops.std
Tests mapping file	n/a

Setup time	Thu Sep 05 04:09:16 2024
Start time	Thu Sep 05 04:09:16 2024
End time	Thu Sep 05 04:12:36 2024
Test duration	3 minutes 20 seconds
Product	n/a
Program	rahmana_i8243_p1.igxl
Revision	n/a
Lot	n/a
Sub−Lot	n/a
WaferID	n/a
Parts processed	All Data / parts (any Bin)
Data from Sites	All sites
Test time (GOOD parts)	2.832 sec. (excludes tester idle time)
Test time (ALL parts)	2.832 sec. (excludes tester idle time)
Average test time	4.000 sec. / device (includes tester idle time between parts)
Total parts tested	50 − Includes parts retested (if any)
Good parts (Yield)	50 (100.00%) − Includes parts retested (if any)
Bad parts (Yield loss)	0 (0.00%) − Includes parts retested (if any)
Parts retested	n/a .
Parts aborted	0 (0.00%)
(null)	−
STDF Version	4.0
Tester name	SNG−UFP−789
Tester type	UltraFLEXplus
Station	1
Part type	n/a
Operator	rahmana
Exec_type	IG−XL
Exec_version	10.30.10_uflx (P1.11)
TestCode	n/a
Test Temperature	n/a
User Text	n/a
Aux_file	n/a
Package type	n/a
Per_freq	n/a
Spec_name	n/a
Spec_version	n/a
Family ID	n/a

Date code	n/a
Design Rev	n/a
Facility ID	n/a
Floor ID	n/a
Proc ID	n/a
Flow ID	n/a
Setup ID	n/a
Eng ID	n/a
ROM code	n/a
Serial #	n/a
Super user name	n/a
Handler/Prober	n/a
(null)	–
Site details	Site# 0

Global Options

Test# policy	Never merge tests with identical test number if test name not matching
Data Cleaning	None (keep all data)
Statistics computation	From samples data (if any), otherwise from summary
Binning computation	From summary data (if any), otherwise from samples
Cp,Cpk computation	Use standard Sigma formula
Mean drift formula	Percentage of value drift